

Irish Standard I.S. EN IEC 61163-2:2020

### Reliability stress screening - Part 2: Components

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#### I.S. EN IEC 61163-2:2020

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This document is based on:

Published:

EN IEC 61163-2:2020

2020-05-01

This document was published under the authority of the NSAI and comes into effect on:

ICS number:

2020-05-18

NOTE: If blank see CEN/CENELEC cover page

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**EN IEC 61163-2** 

NORME EUROPÉENNE

**EUROPÄISCHE NORM** 

May 2020

ICS 03.120.01; 31.020

#### **English Version**

## Reliability stress screening - Part 2: Components (IEC 61163-2:2020)

Déverminage sous contraintes - Partie 2: Composants (IEC 61163-2:2020)

Zuverlässigkeitsvorbehandlung durch Beanspruchung - Teil 2: Bauelemente (IEC 61163-2:2020)

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#### EN IEC 61163-2:2020 (E)

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The text of document 56/1875/FDIS, future edition 2 of IEC 61163-2, prepared by IEC/TC 56 "Dependability" was submitted to the IEC-CENELEC parallel vote and approved by CENELEC as EN IEC 61163-2:2020.

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IEC 62506	NOTE	Harmonized as EN 62506
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IEC 61709	NOTE	Harmonized as EN 61709
IEC 61649	NOTE	Harmonized as EN 61649
IEC 62740	NOTE	Harmonized as EN 62740



IEC 61163-2

Edition 2.0 2020-03

## INTERNATIONAL STANDARD

## NORME INTERNATIONALE

Reliability stress screening – Part 2: Components

Déverminage sous contraintes – Partie 2: Composants





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IEC 61163-2

Edition 2.0 2020-03

### INTERNATIONAL STANDARD

## NORME INTERNATIONALE

Reliability stress screening – Part 2: Components

Déverminage sous contraintes – Partie 2: Composants

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ELECTROTECHNICAL
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ICS 03.120.01; 31.020 ISBN 978-2-8322-7910-6

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**RELIABILITY STRESS SCREENING -**

# Part 2: Components FOREWORD

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This second edition cancels and replaces the first edition published in 1998. This edition constitutes a technical revision.

This edition includes the following significant technical changes with respect to the previous edition:

a) this version of the document is a complete rewrite and restructure from the previous version.

The text of this International Standard is based on the following documents:

FDIS	Report on voting
56/1875/FDIS	56/1887/RVD

Full information on the voting for the approval of this International Standard can be found in the report on voting indicated in the above table.

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This document has been drafted in accordance with the ISO/IEC Directives, Part 2.

A list of all parts in the IEC 61163 series, published under the general title *Reliability stress* screening, can be found on the IEC website.

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#### INTRODUCTION

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Although first developed to stabilize the parameters of manufactured components (burn-in), reliability stress screening (RSS) can be used to remove from a component population the weaker components. This can be done at times where the manufacturing processes for components are difficult to control or for other reasons such as where the components need to be selected (re-qualified) to operate in harsher than usual operating conditions. This is also done where more narrow specifications are required for the application and no alternative courses of action are available.

The use of RSS is normally only a temporary measure when early failures need to be avoided under a specific set of conditions as outlined above.

RSS is an effective tool in identifying and removing flaws due to poor component design and manufacturing deficiencies.

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#### RELIABILITY STRESS SCREENING -

#### Part 2: Components

#### 1 Scope

This part of IEC 61163 provides guidance on RSS techniques and procedures for electrical, electronic, and mechanical components. This document is procedural in nature and is not, and cannot be, exhaustive with respect to component technologies due to the rapid rate of developments in the component industry.

This document is:

- a) intended for component manufacturers as a guideline;
- b) intended for component users as a guideline to negotiate with component manufacturers on RSS requirements;
- c) intended to allow the planning of an RSS process in house to meet reliability requirements or to allow the re-qualification of components for specific, upgraded, environments;
- d) intended as a guideline to sub-contractors who provide RSS as a service.

This document is not intended to provide test plans for specific components or for delivery of certificates of conformance for batches of components.

The use of bi-modal Weibull analysis to select and optimize an RSS process without having to estimate the reliability and life time of all items is described.

#### 2 Normative references

There are no normative references in this document.

#### 3 Terms and definitions

For the purposes of this document, the following terms and definitions apply.

ISO and IEC maintain terminological databases for use in standardization at the following addresses:

- IEC Electropedia: available at http://www.electropedia.org/
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#### 3.1

#### screen

conditions, for example stress level and duration, used for the removal of non-conforming items from a population

#### 3.2

#### screening

process carried out to detect and remove non-conforming items, or those susceptible to early life failure

Note 1 to entry: Screening may employ representative or elevated stresses.



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